(U//FOUO) Scheduled for Today: A&P Analytic Showcase on 'Using Renoir'

FROM: Joe Mercurio
Advanced Analysis Lab (S22A)
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(U//FOUO) You are invited to attend the next Analysis & Production Analytic Showcase to be held on Thursday, **1 June 2006, 1000-1100, in Room 2B4118-6.** The overall classification for the briefing will be TOP SECRET // COMINT. We hope that many of you will attend. Attendance is open and seating is available on a first-come, first-served basis.

SPEAKER: ███████████████, Contractor, SWComplete Member of InfoVis Team, S202B12, formerly S21211

TITLE: (U) *Using Renoir to Manage Dirty Data, Changing Numbering Plans, and Other Anomalies*

Summary:
(U//FOUO) This presentation will illustrate how to use Renoir's "Combine Nodes by Attribute Matching" feature to normalize basic anomalies found in data. Often when data is visualized in a graph, there are instances of duplicate entities because of either missing data, incorrect data, or changing data. The "Combine Nodes by Attribute Matching" feature gives the analyst the capability of removing the duplicity, resulting in a clearer visualization and a more accurate analysis.

(U//FOUO) The Analysis & Production Analytic Showcase provides a periodic forum for the Analysis and Production Offices to share with the work force both the accomplishments and obstacles impacting the NSA/CSS SIGINT mission. The intent is to focus on timely and current events, ideas, products, successes, systemic issues and obstacles, or collaborative efforts that are shaping, enabling, and impacting the Agency's mission to meet and satisfy our customers' information needs.

(U) For questions regarding the A&P Showcase, please visit our web page or contact Joe Mercurio ████████ S22A, ████████ ████████████

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